

Notice of References Cited	Application/Control No. 10/715,264	Applicant(s)/Patent Under Reexamination BROWN, NATHAN R.	
	Examiner Sylvia R. MacArthur	Art Unit 1763	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,270,397	08-2001	Wu, Hsiao Che	451/288
*	B	US-6,594,542	07-2003	Williams, Roger O.	438/692
*	C	US-6,623,333	09-2003	Patel et al.	451/9
*	D	US-6,454,899	09-2002	Campbell et al.	156/345.24
*	E	US-6,442,496	08-2002	Pasadyn et al.	702/83
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*	G	US-6,857,947	02-2005	Wang et al.	451/296
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Merriam-Webster's Collegiate Dictionary, 10 th Edition, the definition of "metrology". pages 1-3
	V	Merriam-Webster's Collegiate Dictionary, 10th Edition, the definition of "topography". page 4 (page 1244)
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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